Notice of References Cite	d
---------------------------	---

Application/Control No.	Applicant(s)/Pater	nt Under
10/590,872	Reexamination TAKAI ET AL.	
Examiner	Art Unit	
EVAN DZIERZYNSKI	2875	Page 1 of 1

## U.S. PATENT DOCUMENTS

	O.S. I ATENT DOCUMENTS				
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2003/0026085 A1	02-2003	Ueda et al.	362/31
*	В	US-2004/0070328 A1	04-2004	Van den Bergh et al.	313/461
*	С	US-2004/0125458 A1	07-2004	Chen et al.	359/599
*	D	US-2004/0251837 A1	12-2004	Leung et al.	315/076
*	Е	US-2005/0246958 A1	11-2005	Weder, Donald E.	047/072
*	ш	US-2005/0276072 A1	12-2005	Hayashi et al.	362/609
	ø	US-			
	I	US-			
	-	US-			
	7	US-			
	к	US-			
	٦	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

	FOREIGN PATENT DOCUMENTS					
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ν					
	0					
	Р					
	Q					
	R					
	s					
	т					

## NON-PATENT DOCUMENTS

	NON-FATENT DOCUMENTS					
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
Ī	v					
	w					
	x					

A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.